



SLOVENSKI STANDARD

SIST EN 62047-1:2016

01-julij-2016

Nadomešča:
SIST EN 62047-1:2007

Polprevodniški elementi - Mikroelektromehanski elementi - 1. del: Izrazi in definicije (IEC 62047-1:2016)

Semiconductor devices - Micro-electromechanical devices - Part 1: Terms and definitions (IEC 62047-1:2016)

iTeh STANDARD PREVIEW
(standards.iteh.ai)

[SIST EN 62047-1:2016](https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-b1933cfe5/sist-en-62047-1-2016)

[https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-](https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-b1933cfe5/sist-en-62047-1-2016)

Ta slovenski standard je istoveten z: EN 62047-1:2016

ICS:

01.040.31	Elektronika (Slovarji)	Electronics (Vocabularies)
31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general

SIST EN 62047-1:2016

en

iTeh STANDARD PREVIEW
(standards.iteh.ai)

SIST EN 62047-1:2016

<https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-24d483fccfe5/sist-en-62047-1-2016>

EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 62047-1

April 2016

ICS 31.080.99

Supersedes EN 62047-1:2006

English Version

**Semiconductor devices - Micro-electromechanical devices - Part
1: Terms and definitions
(IEC 62047-1:2016)**

Dispositifs à semi-conducteurs - Dispositifs
microélectromécaniques - Partie 1: Termes et définitions
(IEC 62047-1:2016)

Halbleiterbauelemente - Bauelemente der
Mikrosystemtechnik - Teil 1: Begriffe
(IEC 62047-1:2016)

This European Standard was approved by CENELEC on 2016-02-10. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.



European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 62047-1:2016**European foreword**

The text of document 47F/232/FDIS, future edition 2 of IEC 62047-1, prepared by SC 47F "Microelectromechanical systems" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62047-1:2016.

The following dates are fixed:

- latest date by which the document has to be (dop) 2016-11-10
implemented at national level by
publication of an identical national
standard or by endorsement
- latest date by which the national (dow) 2019-02-10
standards conflicting with the
document have to be withdrawn

This document supersedes EN 62047-1:2006.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard IEC 62047-1:2016 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 62047-1:2005

NOTE Harmonized as EN 62047-1:2006.

<https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-24d483fccfe5/sist-en-62047-1-2016>



IEC 62047-1

Edition 2.0 2016-01

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices – Micro-electromechanical devices –
Part 1: Terms and definitions**

**Dispositifs à semiconducteurs – Dispositifs microélectromécaniques –
Partie 1: Termes et définitions**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

ICS 31.080.99

ISBN 978-2-8322-3099-2

**Warning! Make sure that you obtained this publication from an authorized distributor.
Attention! Veuillez vous assurer que vous avez obtenu cette publication via un distributeur agréé.**

CONTENTS

FOREWORD	3
1 Scope	5
2 Terms and definitions	5
2.1 General terms and definitions	5
2.2 Terms and definitions relating to science and engineering	6
2.3 Terms and definitions relating to materials science	7
2.4 Terms and definitions relating to functional element	7
2.5 Terms and definitions relating to machining technology	12
2.6 Terms and definitions relating to bonding and assembling technology	19
2.7 Terms and definitions relating to measurement technology	21
2.8 Terms and definitions relating to application technology	23
Annex A (informative) Standpoint and criteria in editing this glossary	27
A.1 Guidelines for selecting terms	27
A.2 Guidelines for writing the definitions	27
A.3 Guidelines for writing the notes	27
Annex B (informative) Clause cross-references of IEC 62047-1:2005 and IEC 62047-1:2015	28
Bibliography	32
Table B.1 – Clause cross-reference of IEC 62047-1: 2005 and IEC 62047-1:2015	28

[SIST EN 62047-1:2016](https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-24d483fccfe5/sist-en-62047-1-2016)
<https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-24d483fccfe5/sist-en-62047-1-2016>

INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 1: Terms and definitions

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
<https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-24d483fcfcf5/sist-en-62047-1-2016>
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 62047-1 has been prepared by subcommittee 47F: Micro-electromechanical systems, of IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2005. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) removal of ten terms;
- b) revision of twelve terms;
- c) addition of sixteen new terms.

The text of this standard is based on the following documents:

FDIS	Report on voting
47F/232/FDIS	47F/238/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62047 series, published under the general title *Semiconductor devices – Micro-electromechanical devices*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

iTeh STANDARD PREVIEW
(standards.iteh.ai)

SIST EN 62047-1:2016

<https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-24d483fccfe5/sist-en-62047-1-2016>

SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 1: Terms and definitions

1 Scope

This part of IEC 62047 defines terms for micro-electromechanical devices including the process of production of such devices.

2 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

2.1 General terms and definitions

2.1.1

micro-electromechanical device

micro-sized device, in which sensors, actuators, transducers, resonators, oscillators, mechanical components and/or electric circuits are integrated

Note 1 to entry: Related technologies are extremely diverse from fundamental technologies such as design, material, processing, functional element, system control, energy supply, bonding and assembly, electric circuit, and evaluation to basic science such as micro-science and engineering as well as thermodynamics and tribology in a micro-scale. If the devices constitute a system it is sometimes called as MEMS which is an acronym standing for "micro-electromechanical systems"

2.1.2

MST

microsystem technology

technology to realize microelectrical, optical and machinery systems and even their components by using micromachining

Note 1 to entry: The term MST is mostly used in Europe.

Note 2 to entry: This note applies to the French language only.

2.1.3

micromachine

2.1.3.1

micromachine, <device>

miniaturized device, the components of which are several millimetres or smaller in size

Note 1 to entry: Various functional device (such as a sensor that utilizes the micromachine technology) is included.

2.1.3.2

micromachine, <system>

microsystem that consists of an integration of micromachine devices

Note 1 to entry: A molecular machine called a nanomachine is included.

2.2 Terms and definitions relating to science and engineering

2.2.1

micro-science and engineering

science and engineering for the microscopic world of MEMS

Note 1 to entry: When mechanical systems are miniaturized, various physical parameters change. Two cases prevail: 1) these changes can be predicted by extrapolating the changes of the macro-world, and 2) the peculiarity of the microscopic world becomes apparent and extrapolation is not possible. In the latter case, it is necessary to establish new theoretical and empirical equations for the explanation of phenomena in the microscopic world. Moreover, new methods of analysis and synthesis to deal with engineering problems must be developed. Materials science, fluid dynamics, thermodynamics, tribology, control engineering, and kinematics can be systematized as micro-sciences and engineering supporting micromechanics.

2.2.2

scale effect

change in effect on the object's behaviour or properties caused by the change in the object's dimension

Note 1 to entry: The volume of an object is proportional to the third power of its dimension, while the surface area is proportional to the second power. As a result, the effect of surface force becomes larger than that of the body force in the microscopic world. For example, the dominant force in the motion of a microscopic object is not the inertial force but the electrostatic force or viscous force. Material properties of microscopic objects are also affected by the internal material structure and surface, and, as a result, characteristic values are sometimes different from those of bulks. Frictional properties in the microscopic world also differ from those in the macroscopic world. Therefore, those effects must be considered carefully while designing a micromachine.

2.2.3

microtribology

tribology for the microscopic world [SIST EN 62047-1:2016](https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-7c1d4835d85e/iec-62047-1-2016)

[https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-](https://standards.iteh.ai/catalog/standards/sist/241401c4-485e-448e-a3d0-7c1d4835d85e/iec-62047-1-2016)

Note 1 to entry: Tribology deals with friction and wear in the macroscopic world. On the other hand, when the dimensions of components such as those in micromachines become extremely small, surface force and viscous force become dominant instead of gravity and inertial force. According to Coulomb's law of friction, frictional force is proportional to the normal load. In the micromachine environment, because of the reaction between surface forces, a large frictional force occurs that would be inconceivable in an ordinary scale environment. Also a very small quantity of abrasion that would not be a problem in an ordinary scale environment can fatally damage a micromachine. Microtribology research seeks to reduce frictional forces and to discover conditions that are free of friction, even on an atomic level. In this research, observation is made of phenomena that occur with friction surfaces or solid surfaces at from angstrom to nanometer resolution, and analysis of interaction on an atomic level is performed. These approaches are expected to be applied in solving problems in tribology for the ordinary scale environment as well as for the micromachine environment.

2.2.4

biomimetics

creating functions that imitate the motions or the mechanisms of organisms

Note 1 to entry: In devising microscopic mechanisms suitable for micromachines, the mechanisms and structures of organisms that have survived severe natural selection may serve as good examples to imitate. One example is the microscopic three-dimensional structures that were modelled on the exoskeletons and elastic coupling systems of insects. In exoskeletons, a hard epidermis is coupled with an elastic body, and all movable parts use the deformation of the elastic body to move. The use of elastic deformation would be advantageous in the microscopic world to avoid friction. Also, the exoskeleton structure equates to a closed link mechanism in kinematics and has the characteristic that some actuator movement can be transmitted to multiple links.

2.2.5

self-organization

organization of a system without any external manipulation or control, where a nonequilibrium structure emerges spontaneously due to the collective interactions among a number of simple microscopic objects or phenomena

2.2.6**electro wetting on dielectric****EWOD**

wetting of a substrate controlled by the voltage between a droplet and the substrate covered with a dielectric film

Note 1 to entry: The contact angle of a liquid droplet, typically an electrolyte, on a substrate can be electrically controlled because the solid-liquid surface interfacial tension can be controlled with the energy stored in the electric double layer which works as capacitor. Covering the electrode with a dielectric material of determined thickness, the capacitance can be determined with ease. Electro wetting on dielectric is used typically in microfluidic devices.

Note 2 to entry: This note applies to the French language only.

2.2.7**stiction**

phenomenon that a moving microstructure is stuck to another structure or substrate by adhesion forces

Note 1 to entry: When structures become smaller, stiction appears significant due to the scale effect that surface forces predominate over body forces. Stiction frequently occurs in the MEMS fabrication process when small structures are released during wet etching processes due to the surface tension of liquid. Representative adhesion forces to cause stiction are van der Waals force, electrostatic force, and surface tension of liquid between structures.

2.3 Terms and definitions relating to materials science**2.3.1****silicon-on-insulator****SOI**

structure composed of an insulator and a thin layer of silicon on it

Note 1 to entry: Sapphire (as in SOS), glass (as in SOG), silicon dioxide, silicon nitride, or even an insulating form of silicon itself is used as an insulator.

Note 2 to entry: This note applies to the French language only.

2.4 Terms and definitions relating to functional element**2.4.1****actuator, <micro-electromechanical devices>**

mechanical device that converts non-kinetic energy into kinetic energy to perform mechanical work

2.4.2**microactuator**

actuator produced by micromachining

Note 1 to entry: For a micromachine to perform mechanical work, the microactuator is indispensable as a basic component. Major examples are the electrostatic actuator prepared by silicon process, the piezoelectric actuator that utilizes functional materials like lead zirconate titanate (PZT), the pneumatic rubber-actuator, and so on. Many other actuators based on various energy conversion principles have been investigated and developed. However, the energy conversion efficiency of all these actuators deteriorates as their size is reduced. Therefore, the motion mechanisms of organisms such as the deformation of protein molecules, the flagellar movement of bacteria, and muscle contraction are being utilized to develop special new actuators for micromachines.

Note 2 to entry: Micro-electrostatic actuators are actuated by a micro-electrostatic field, magnetic microactuators are driven by a micromagnetic field, and piezoelectric microactuators depend on a microstress field to convey motion and power.

2.4.3**light-driven actuator**

actuator that uses light as a control signal or an energy source or both

Note 1 to entry: Since the development of photostrictive materials, various light driven actuators have been proposed. These actuators have simple structures and can be driven by wireless means. A motor is proposed that utilizes the spin realignment effect, in which a magnetic material absorbs light and the resulting heat changes the direction of magnetization reversibly. Actuators utilizing thermal expansion, and exploiting polymer photochemical reactions, are also being studied.

2.4.4**piezoelectric actuator**

actuator that uses piezoelectric material

Note 1 to entry: Piezoelectric actuators are classified into the single-plate, bimorph, and stacked types, and the popular material is lead zirconate titanate (PZT). The features are: 1) quick response, 2) large output force per volume, 3) ease of miniaturization because of the simple structure, 4) narrow displacement range for easier microdisplacement control, and 5) high efficiency of energy conversion. Piezoelectric actuators are used for the actuators for micromachines, such as ultrasonic motor, and vibrator. An applied example is a piezoelectric actuator for a travelling mechanism which moves by the resonance vibration of a piezoelectric bimorph, and a micropositioner piezoelectric actuator which amplifies the displacements of a stacked piezoelectric device by a lever.

2.4.5**shape-memory alloy actuator**

actuator that uses shape memory alloy

Note 1 to entry: Shape-memory alloy actuators are compact, light, and produce large forces. These actuators can be driven repeatedly in a heat cycle or can be controlled arbitrarily by switching the electric current through the actuator itself. Lately, attempts have been made to use the alloys to build a servosystem that has an appropriate feedback mechanism and a cooling system intended for applications where quick response is not necessary. Application examples under development are microgrippers for cell manipulation, microvalves for regulating very small amounts of flow and active endoscopes for medical use.

2.4.6**sol-gel conversion actuator**

actuator that uses the transition between the sol (liquid) state and the gel (solid) state

Note 1 to entry: A sol-gel conversion actuator can work in a similar way to living things. For example, if electrodes are put on a small particle of sodium polyacrylate gel in an electrolytic solution and a voltage is applied, the particle repeatedly changes its shape. Sol-gel conversion actuators can be connected in series, sealed in a thin pipe and fitted with multiple legs, to make a microrobot that moves in one direction and that looks like a centipede. Another application being conceived is a crawler microrobot that automatically moves through a thin pipe.

2.4.7**electrostatic actuator**

actuator that uses electrostatic force

Note 1 to entry: Since the electrostatic actuator has a simple structure and its output force per weight is increased as the size is reduced, much research is ongoing to apply these characteristics to the actuators of micromachines. Application examples developed so far on an experimental basis include a wobble motor and a film electrostatic actuator.

2.4.8**comb-drive actuator**

electrostatic actuator, consisting of a series of parallel fingers, fixed in position, engaged and interleaved with a second, movable set of fingers

Note 1 to entry: The application of an electrostatic charge to the first set of fingers attracts the fingers of the second set, such that they become more fully engaged in the interdigit spaces of the first set. Then the static